

Notice of References Cited	Application/Control No. 10/577,018		Applicant(s)/Patent Under Reexamination YOSHIYA, SHUN	
	Examiner RICARDO E. LOPEZ		Art Unit 1786	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0154742	08-2003	Ooide, Ryosuke	63/38
	B	US-			
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FOREIGN PATENT DOCUMENTS

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